

QT-Brightek Optocoupler Series

10Mbit/s High Speed Logic Gate Optocoupler

Part No.: 6N137, QT2601

Table of Contents:

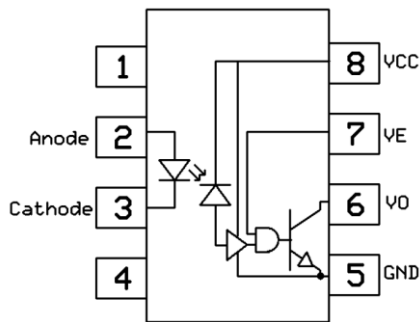
Introduction	3
Absolute Maximum Rating	6
Electrical Characteristic ($T_A=25\text{ }^\circ\text{C}$).....	7
Characteristic Curves.....	9
Test Circuits	11
Solder Profile & Footprint.....	14
Packing & Labeling	16
Device Marking	17
Ordering Information	18
Revision History	19
Disclaimer	19

Introduction

Feature:

- High Speed 10Mbit/s
- High Isolation voltage between input and output (Viso = 5000V rms)
- Creepage distance > 7.4mm
- Available in Tube or Tape and reel
- Available with standard DIP-8, Gullwing lead bend, SMD lead bend, and SMD low profile options.

Schematic:

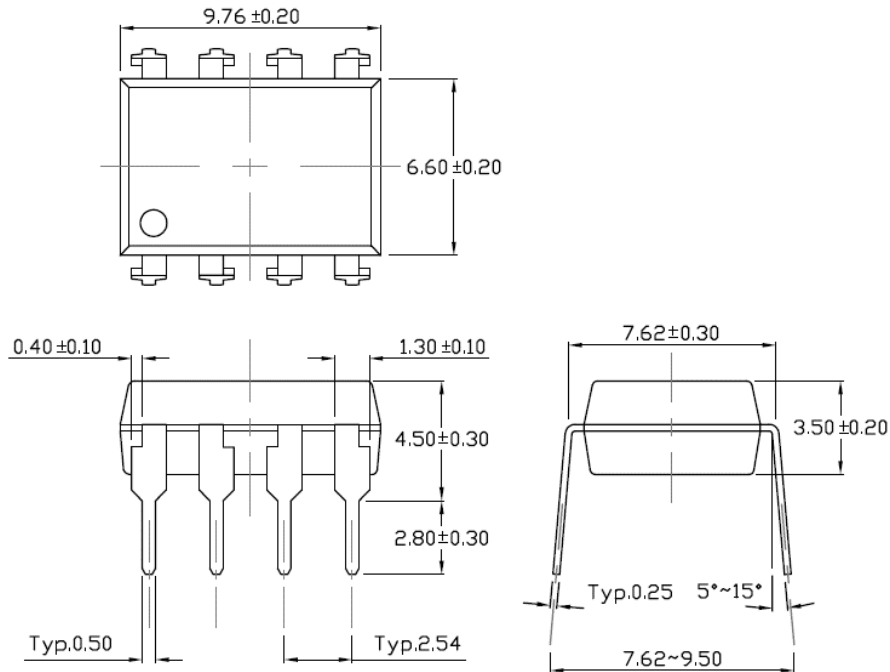


Certification & Compliance:

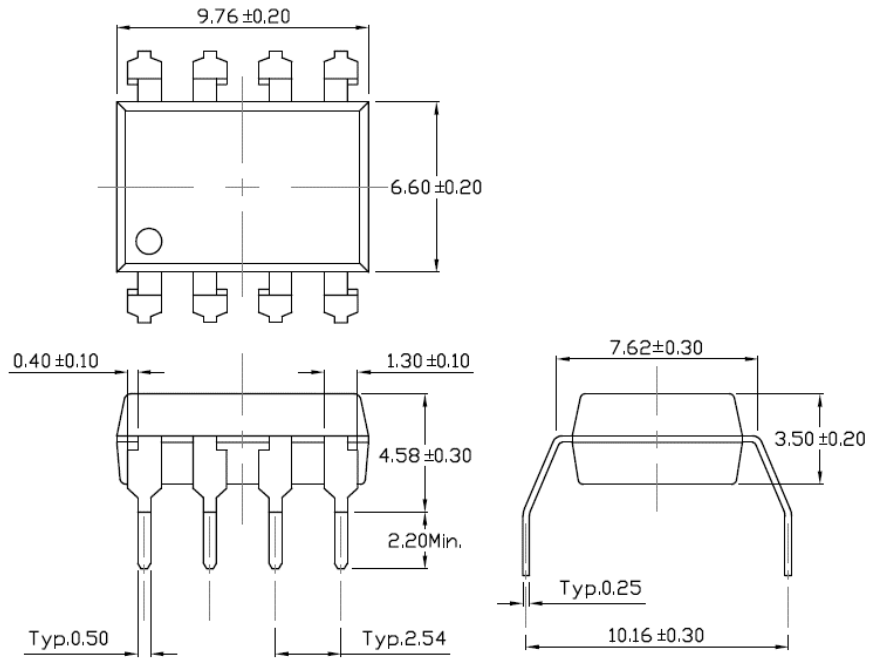
- Pb free and RoHS Compliant
- UL recognized (File #E338132)
- cUL recognized (File #E338132)
- VDE (File #40030457)



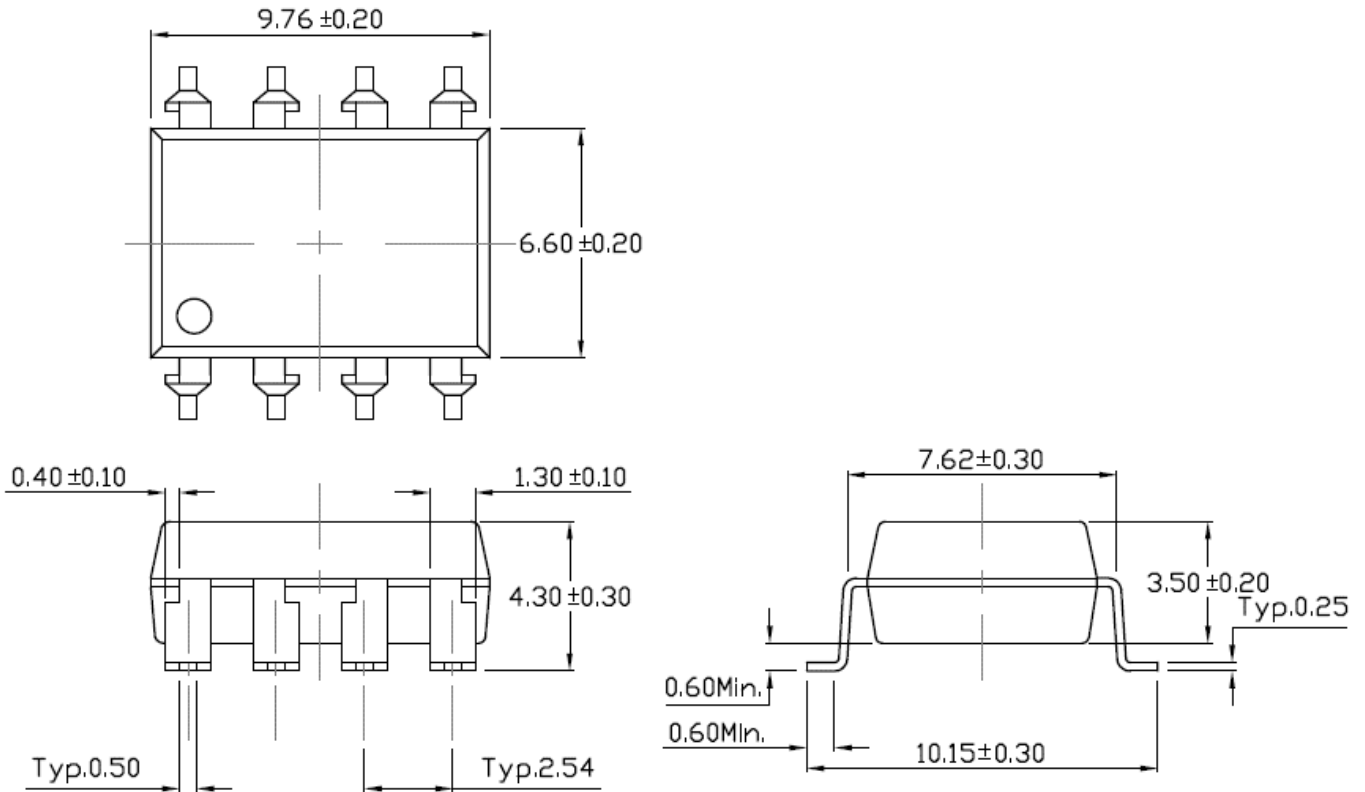
Dimension: (Dot location indicates pin 1) 8-Pin Dip (standard):

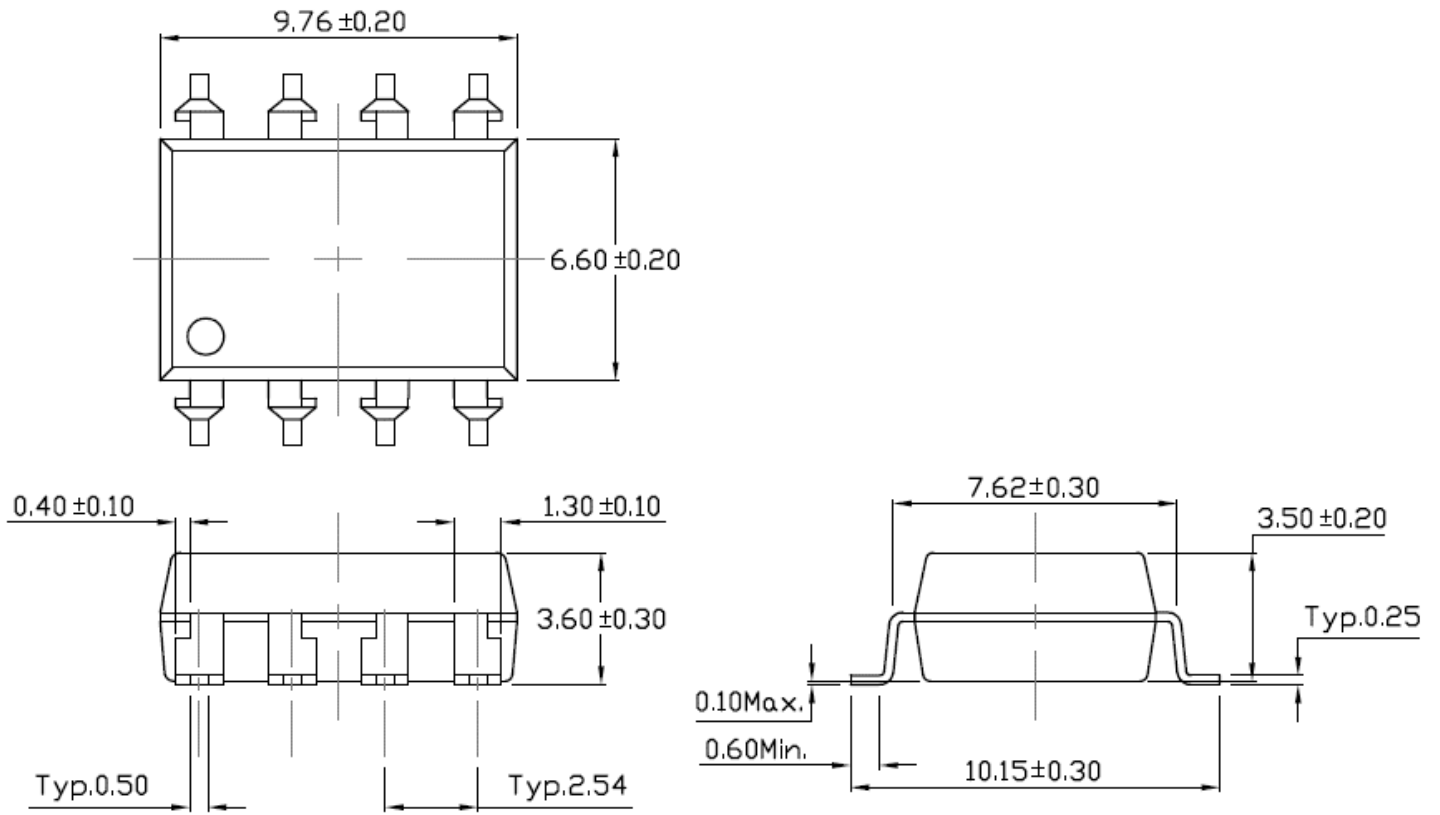


Gullwing (400mil) lead bend (Option M):



SMD lead bend (Option S):



SMD (Low Profile) bend (Option SL):

All Dimensions are in mm

Absolute Maximum Rating

Symbol	Parameter	Rating	Units
V _{ISO}	Isolation Voltage*	5000	V _{RMS}
T _{STG}	Storage Temperature	-55 ~ +125	°C
T _{OPR}	Operating Temperature	-55 ~ +85	°C
T _{SOL}	Lead Solder Temperature	260 for 10 sec	°C
EMITTER			
I _F	Forward Current	50	mA
V _R	Reverse Voltage	5	V
P _I	Power Dissipation	100	mW
	Power Dissipation Derated above 100°C	-	mW/°C
DETECTOR			
P _O	Power Dissipation	85	mW
I _O	Average Output current	50	mA
V _O	Output voltage**	7.0	V
V _{CC}	Supply voltage	7.0	V
VE	Enable Input Voltage Not to Exceed VCC by more than 500mW	5.5	V

*AC for 1 minute, RH =40~60%

**1min (Max.)

Electrical Characteristic (T_A=25 °C)

(T_A=0 to 70C unless specified otherwise)

Emitter

Symbol	Characteristics	Device	Test Condition	Range			Unit
				Min	Typ	Max	
V _F	Forward Voltage	-	I _F = 10mA	-	1.4	1.6	V
V _R	Reverse Voltage		I _R = 10μA	5	-	-	V
ΔV _F /ΔT _A	Temperature coefficient of forward voltage		I _F = 10mA	-	-1.8	-	mV/°C

Detector

Symbol	Characteristic	Device	Test Condition	Range			Unit
				Min	Typ	Max	
I _{CCH}	Logic High Supply Current	-	I _F =0mA, V _E =0.5V, V _{CC} =5.5V	-	6.5	10	mA
I _{CCL}	Logic Low Supply Current	-	I _F =10mA, V _E =0.5V, V _{CC} =5.5V	-	8.8	13	mA
V _{EH}	High Level Enable Voltage	-	I _F =10mA, V _{CC} =5.5V	2.0	-	-	V
V _{EL}	Low Level Enable Voltage	-	I _F =10mA, V _{CC} =5.5V	-	-	0.8	V
I _{EH}	High Level Enable Current	-	V _E =2.0V, V _{CC} =5.5V	-	-0.53	-1.6	mA
I _{EL}	Low Level Enable Current	-	V _E =0.5V, V _{CC} =5.5V	-	-0.75	-1.6	mA

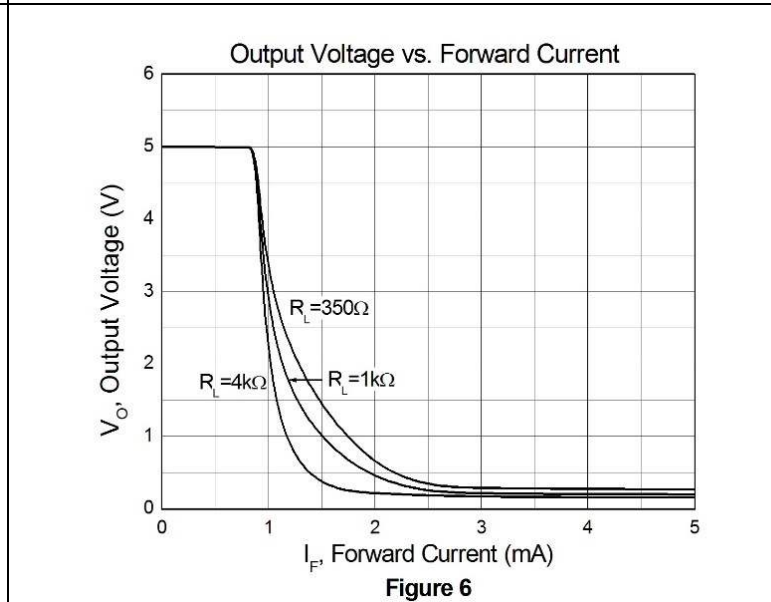
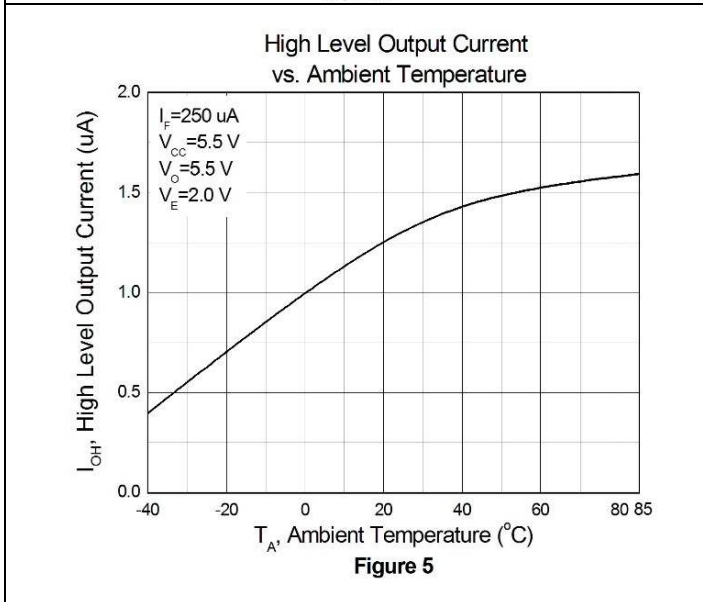
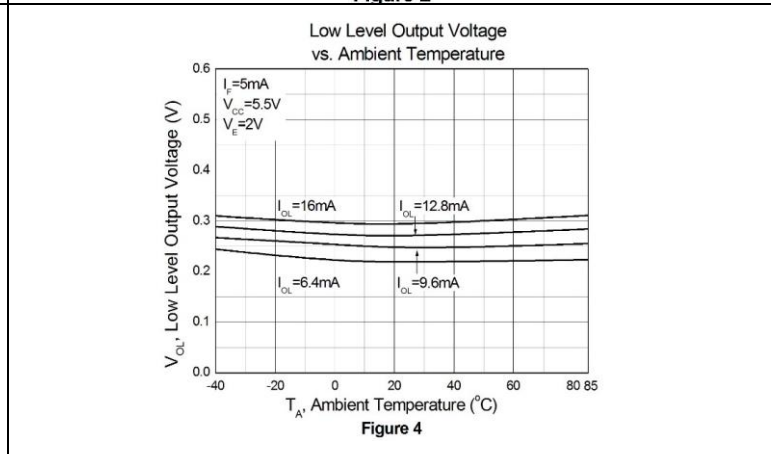
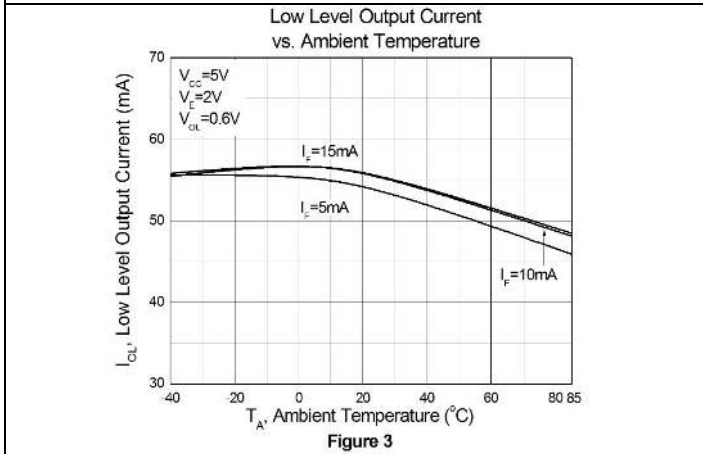
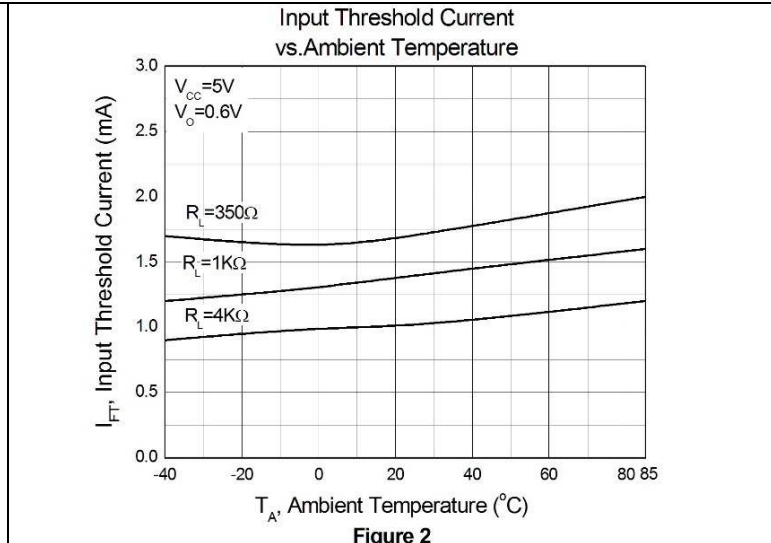
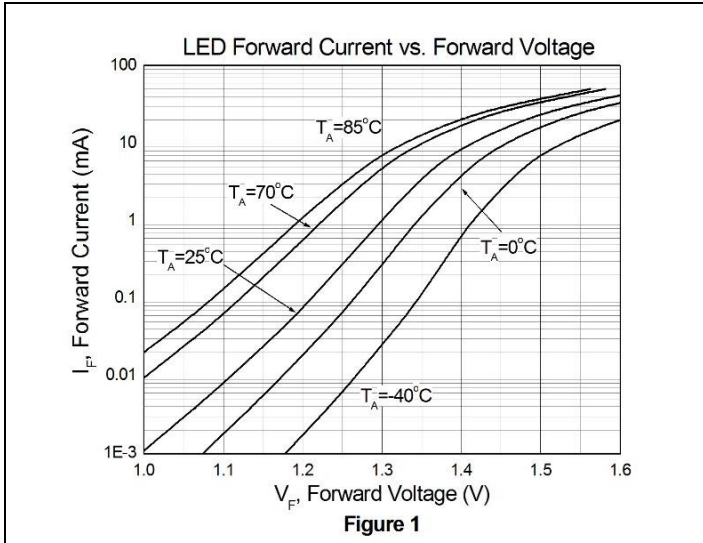
Transfer Characteristics

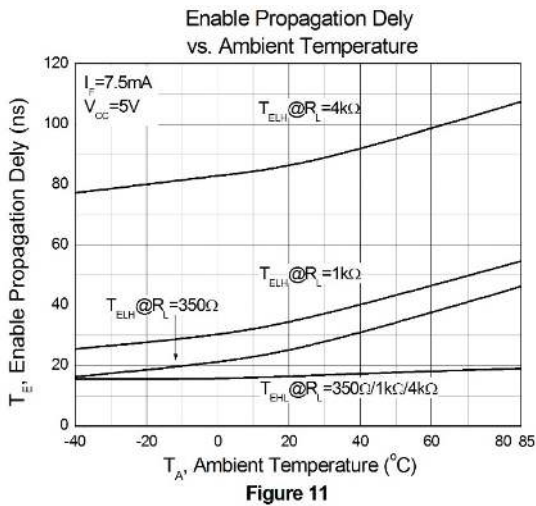
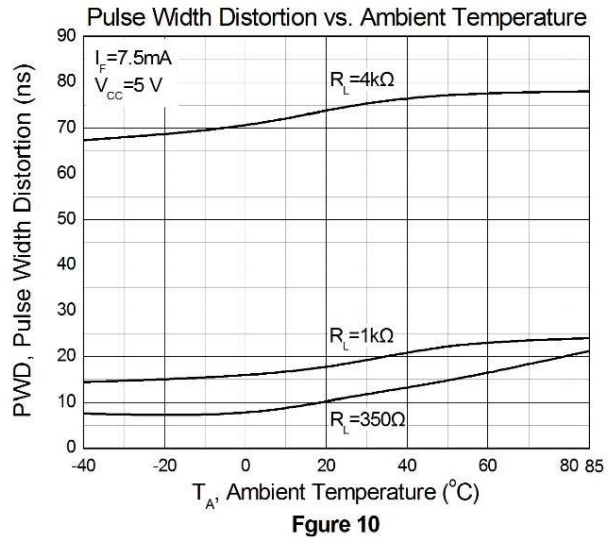
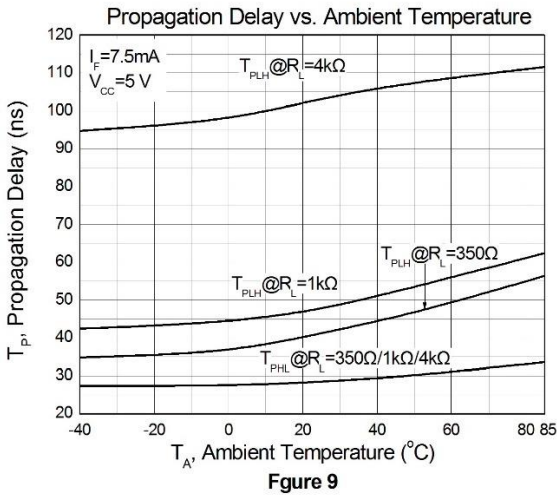
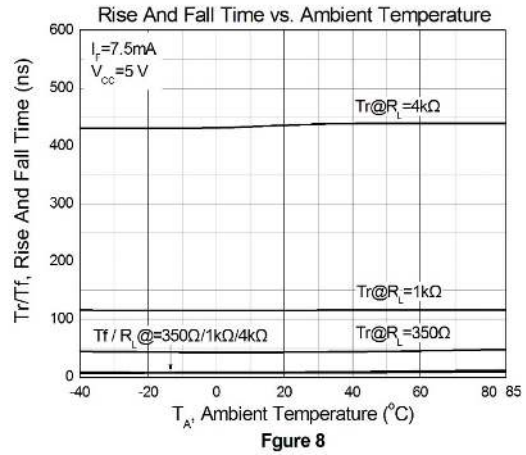
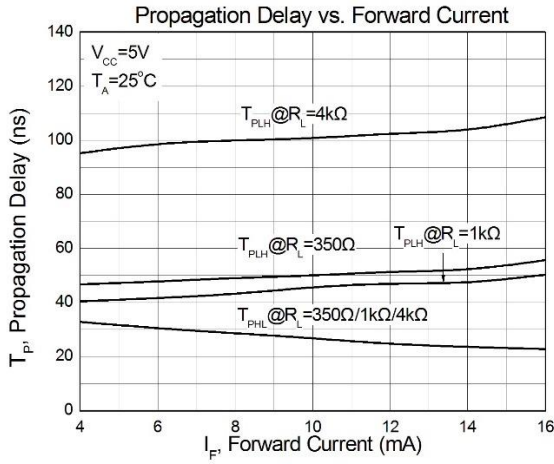
Symbol	Characteristic	Device	Test Condition	Range			Unit
				Min	Typ	Max	
I_{FT}	Input Threshold Current	-	$V_{CC}=5.5V, V_O=0.6V, V_E=2.0V, I_O=13mA$	-	2.5	5	mA
I_{OH}	Logic High Output Current	-	$I_F=250\mu A, V_O=V_{CC}=5.5V, V_E=2.0V$	-	2.0	100	μA
V_{OL}	Logic Low Output Voltage	-	$I_F=5mA, I_O=13mA, V_{CC}=5.5V, V_E=2.0V$	-	0.35	0.6	V

Switching Characteristics (TA=25°C, VCC=5V)

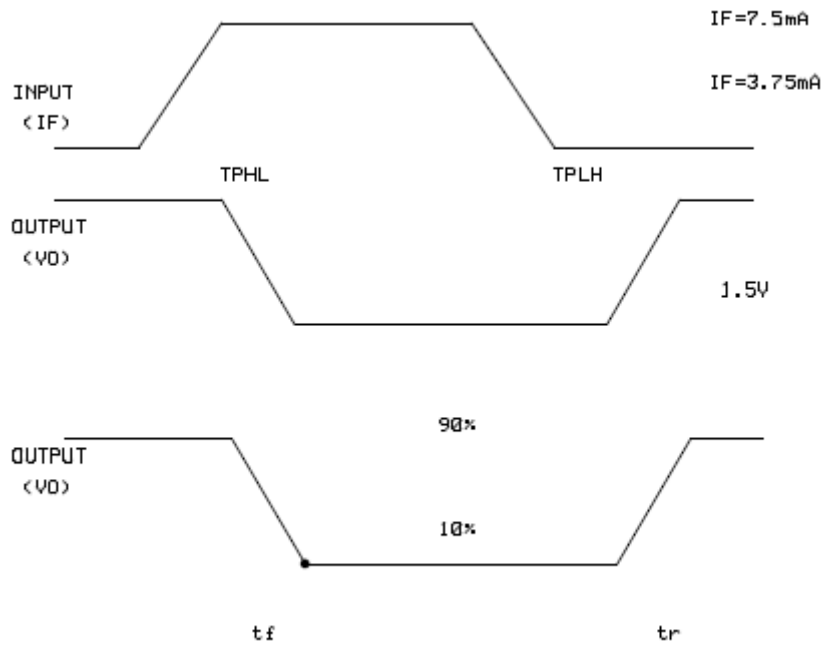
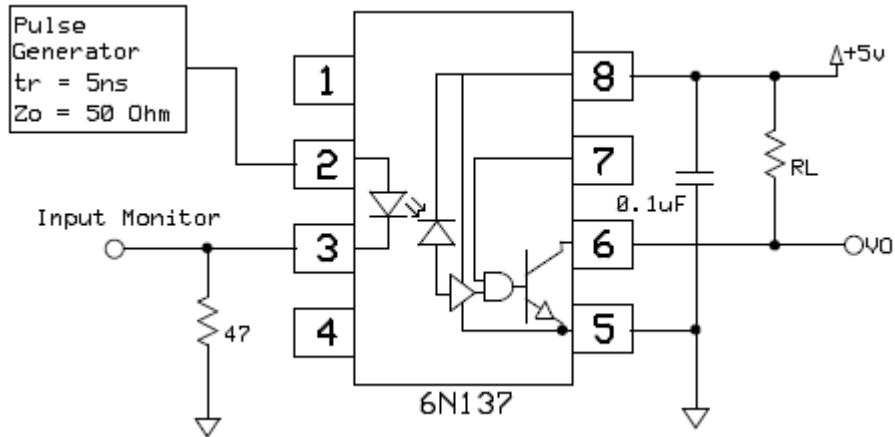
Symbol	Characteristic	Device	Test Condition	Range			Unit
				Min	Typ	Max	
T_{PHL}	Propagation Delay Time Logic High to Logic Low	-	$C_L=15pF, R_L=350\Omega$	-	34	75	ns
T_{PLH}	Propagation Delay Time Logic Low to Logic High	-		-	39	75	
P_{WD}	Pulse Width Distortion	-		-	5	34	
T_r	Output Rise Time	-		-	37	-	
T_f	Output Fall Time	-		-	10	-	
T_{ELH}	Enable Propagation Delay Low To High	-	$V_{EH}=3.5V, C_L=15pF, R_L=350\Omega$	-	15	-	ns
T_{EHL}	Enable Propagation Delay High To Low	-		-	15	-	ns
CM_H	Common Mode Transient Immunity at Logic High	6N137	$I_F = 0mA, V_{CM}=50Vp-p, V_{OH}=2.0V, R_L=350\Omega$	-	10000	-	V/ μs
		QT2601		5000	10000	-	
CM_L	Common Mode Transient Immunity at Logic Low	6N137	$I_F = 7.5mA, V_{CM}=50Vp-p, V_{OH}=0.8V, R_L=350\Omega$	-	10000	-	
		QT2601		5000	10000	-	

Characteristic Curves

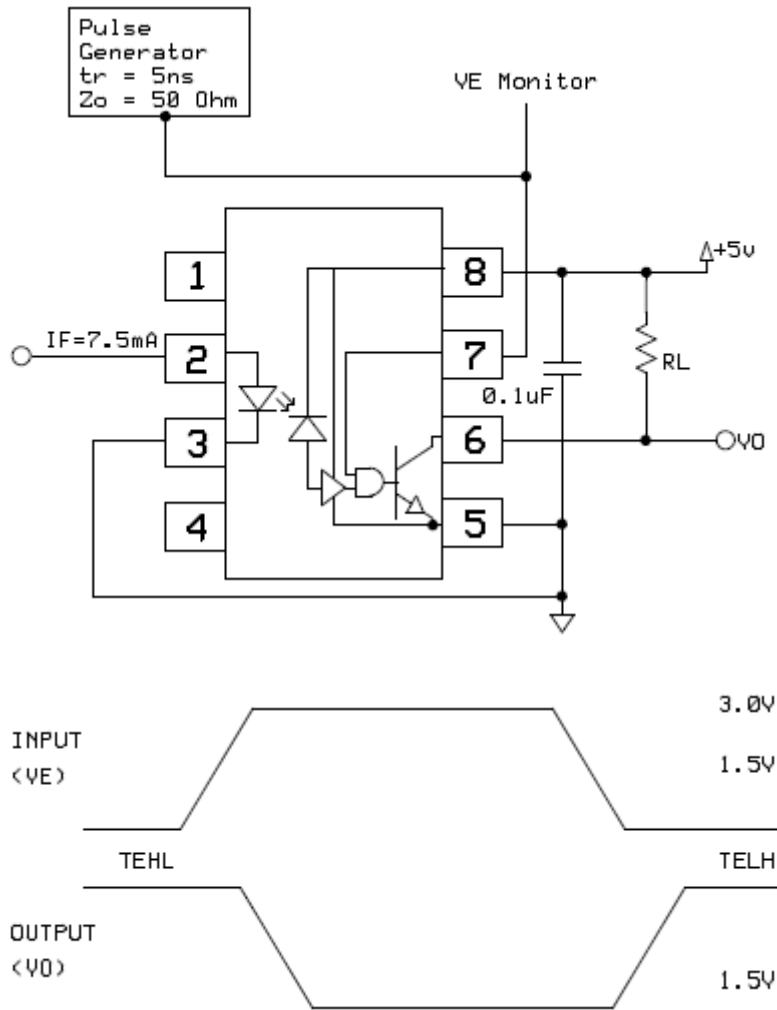




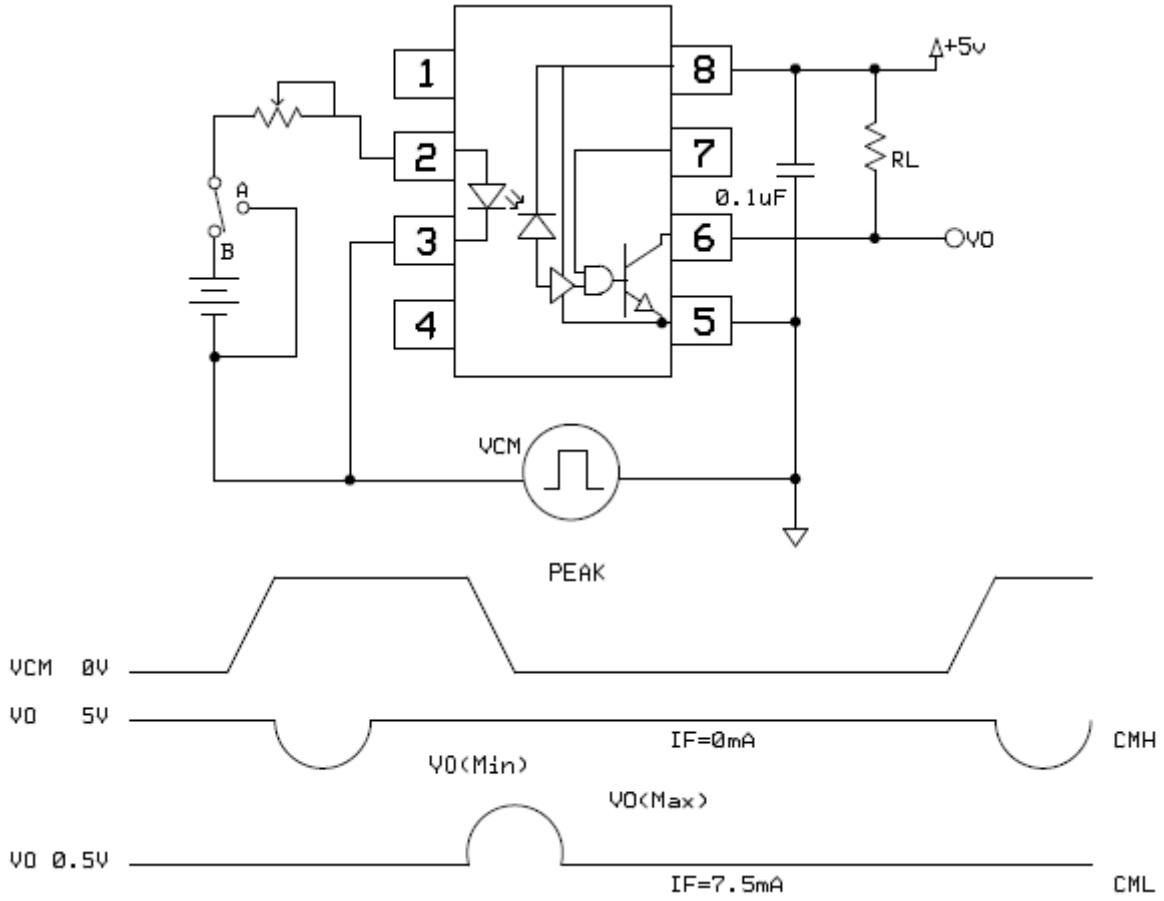
Test Circuits



Switching Time Test Circuit

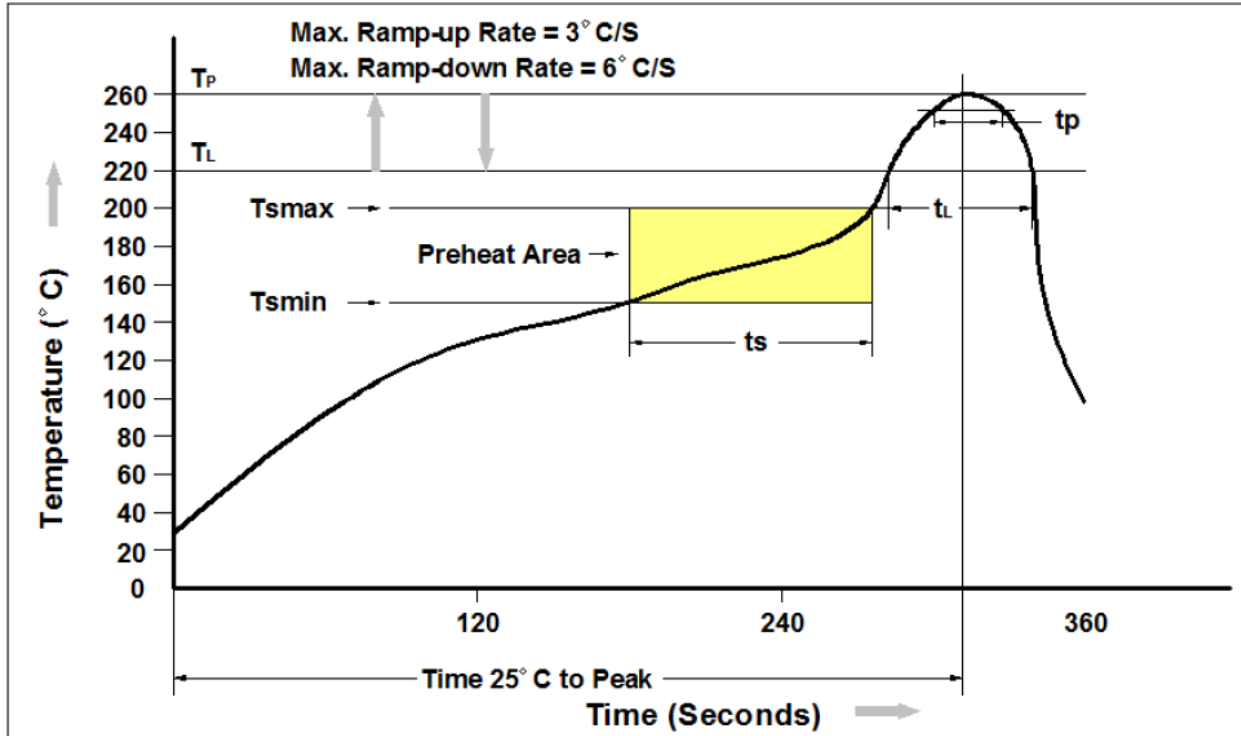


Enable Switching Time Test Circuit

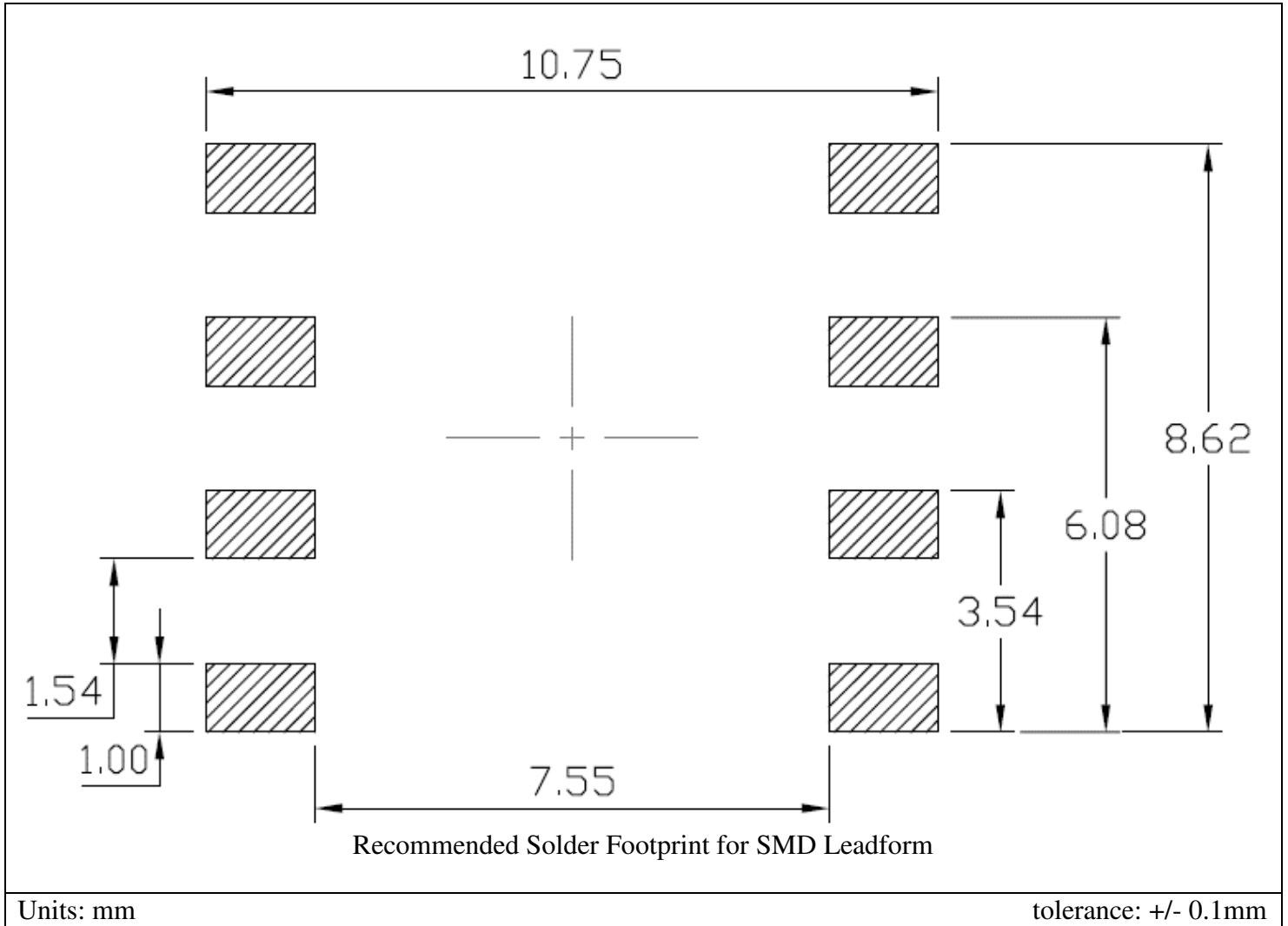


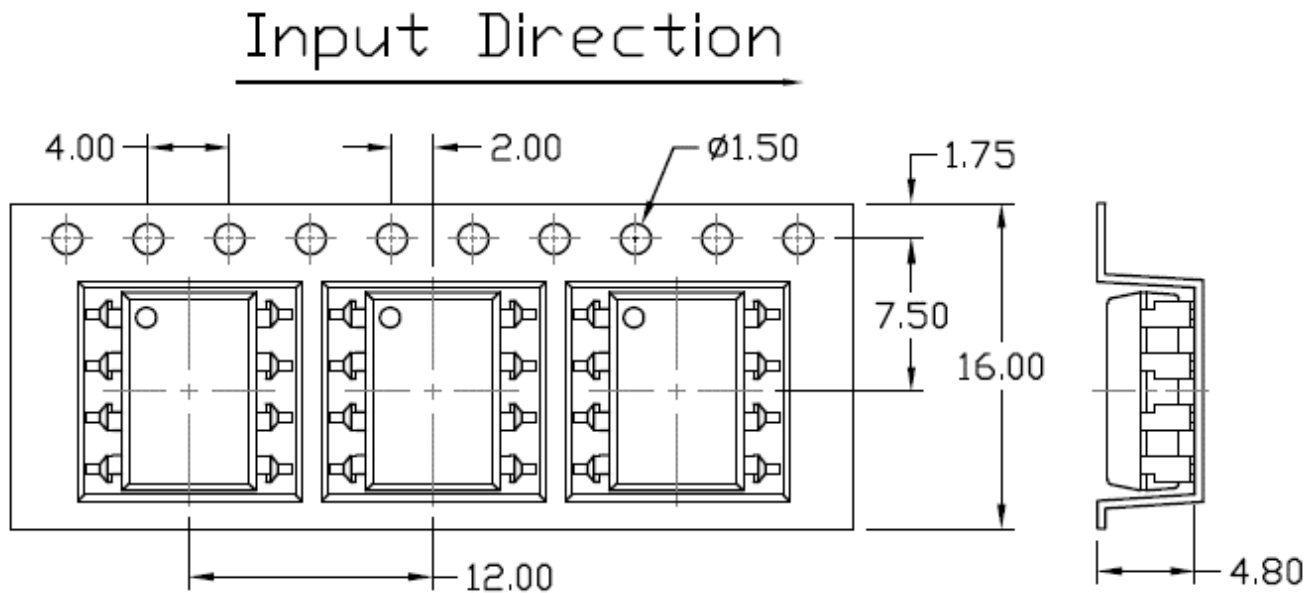
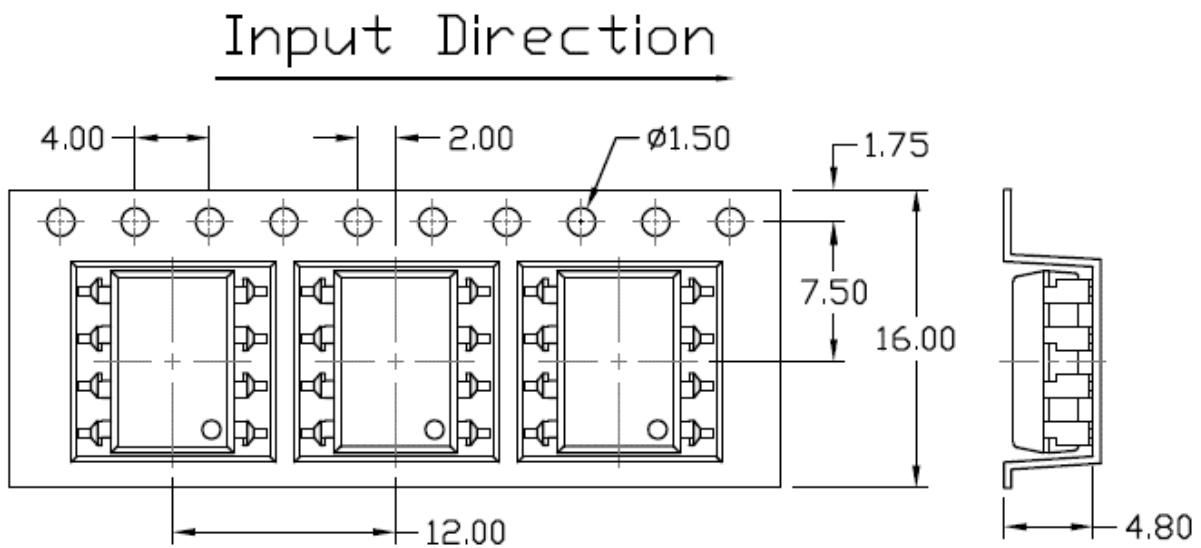
CMR Test Circuit

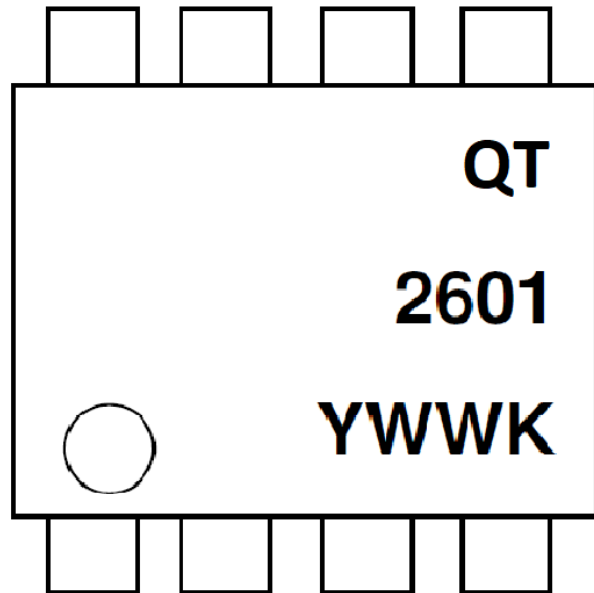
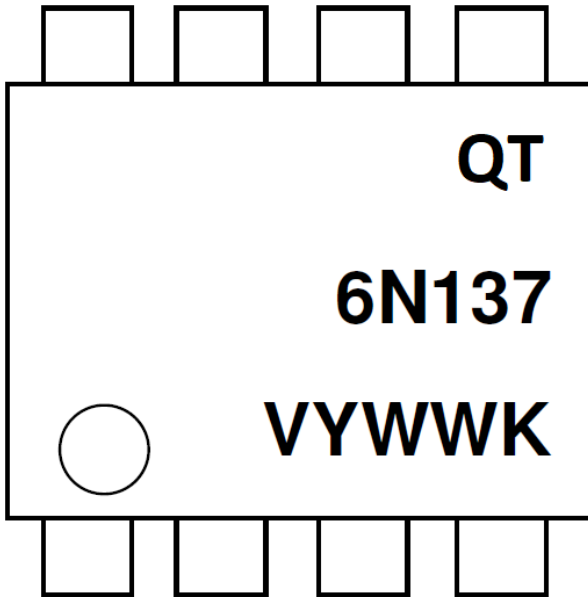
Solder Profile & Footprint



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{smin})	150°C
Temperature Max. (T _{smax})	200°C
Time (t _s) from (T _{smin} to T _{smax})	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t _P) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



Packing & Labeling**Tape Dimension:****Option ST1 & SLT1****Option ST2 & SLT2**

Device Marking

QT = QT-Brightek Corporation
6N135 or 2601 = part number
Y = Year
WW = Week
V = VDE Option
K = Manufacturing code

Ordering Information

6N137VYZ or QT2601VYZ

V = VDE option (V or None)

Y = Lead form option (S, SL, M or none)

Z=Tape and reel option (T1 or T2)

Option	Description	Quantity
None	Standard 8-Pin DIP	40 Units/Tube
M	Gullwing	40 Units/Tube
ST1	Surface Mount Lead Forming – with Option 1 Taping	1000 pcs/ reel
ST2	Surface Mount Lead Forming – with Option 2 Taping	1000 pcs/ reel
SLT1	SMD (Low Profile) Lead Forming – with Option 1 Taping	1000 pcs/ reel
SLT2	SMD (Low Profile) Lead Forming – with Option 2 Taping	1000 pcs/ reel



Revision History

Description:	Revision #	Revision Date
Initial release of 6N137_QT2601	1.0	02/12/2018

Disclaimer

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1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.